

NEWS FROM THE ANALYTICAL INSTRUMENTATION FACILITY (AIF) - OCTOBER 2018

EBSD Workshop

We are pleased to announce an upcoming EBSD Workshop on November 7 or November 8, cohosted by Oxford Instruments and AIF. A lecture will be followed by hands-on training using the latest Symmetry Detector from Oxford on the Verios SEM. Seating for the hands-on portion of the workshop is limited so sign up early!

Register Here »

RTNN 2018 Award Winners

The RTNN awards recognize researchers conducting collaborative research across the network and students who have contributed to outreach activities. Congratulations to Khara Grieger (RTI) and Maryam Khazaee (Duke University and University of Duisburg-Essen) for winning the Collaborative Research Award and to Nicole Smiddy (UNC), Justin Norkett (NC State), and Maxine Gorelick (Duke) for winning the Student Outreach Award.

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National Nanotechnology Day

National Nanotechnology Day is an annual celebration featuring a series of community-led events and activities on or around October 9 (10 to the power -9!) to help raise awareness of nanotechnology, how it is currently used in products that enrich our daily lives, and the challenges and opportunities it holds for the future. Make sure to use #NationalNanoDay and #AIF when you post a story, picture, or anything else on your social media!

Submit Your National Nanotechnology Day Event »

Talos Update

The site agreement tests have been completed on the Talos. The beam is ON now! We are starting to develop user training and operation protocols. We will start to migrate advanced users in about two weeks.

Find Out More »

<u>It's not too late to register for the Carolina Science Symposium!</u>

We are pleased to continue a joint symposium between the Materials Research Society, ASM International and the American Vacuum Society. The meeting is expected to draw about 100 participants, both locally and from the surrounding region. Topics in materials science, processing, nanotechnology, characterization, and biomaterials will be presented by both invited and selected student contributors.

View Details »